

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Zongtao GE

Serial No.: TO BE ASSIGNED

Art Unit: TO BE ASSIGNED

Filed: January 22, 2001

Examiner: TO BE ASSIGNED

For: Phase Shift Fringe Analysis Method and Apparatus Using the  
Same**INFORMATION DISCLOSURE STATEMENT**  
**PURSUANT TO 37 C.F.R. §§ 1.56, 1.97, and 1.98**Assistant Commissioner of  
Patents and Trademarks  
Washington, D.C. 20231

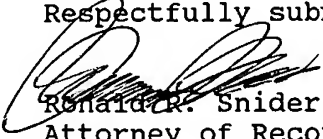
Sir:

In compliance with the dictates of 37 C.F.R. §§ 1.56, 1.97, and 1.98, Applicant hereby submits an Information Disclosure Statement.

The attached documents are mentioned in the present specification and a brief description of their relevance can be found therein.

It is respectfully requested that the Examiner consider each of these references and indicate such consideration by enclosing an appropriately initialled copy of the enclosed form PTO-1449 with the next communication from the Patent Office.

Respectfully submitted,

  
Ronald R. Snider  
Attorney of Record  
Reg. No. 24,962

Date: January 22, 2002

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J. McNeill  
4/6/02

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## PTO FORM 1449 SUBMISSION

U.S. PATENT DOCUMENTS			
Examiner Initials*	U.S. Patent Document Number	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY

FOREIGN PATENT DOCUMENTS				
Examiner Initials*	Foreign Patent Document Number	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T**

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS		
Examiners Initials*	Include Author (CAPITAL LETTERS), title of article, book, magazine, etc. date, page(s), volume-issue number(s), publisher, city and/or country where published	T**
	MITSUO TAKEDA, "Subfringe Interferometry Fundamentals", <u>Kogaku</u> , February 1984, pp. 55-65, Vol. 13, No. 1, Japan	
	KATHERINE CREATH, "Phase-Measurement Interferometry Techniques", <u>Progress in Optics</u> , E. Wolf, Editor, 1988, pp. 349-393, Vol. XXVI, Elsevier Science Publishers B.V., New York, U.S.A.	

Examiner Signature		Date Considered	
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\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

\*\*Applicant is to place a check mark here if English language translation is attached

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